

<b>Notice of References Cited</b>	Application/Control No. 10/517,366	Applicant(s)/Patent Under Reexamination HATANAKA ET AL.	
	Examiner Thao T. Tran	Art Unit 1711	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,797,383	09-2004	Nishizawa et al.	428/412
*	C	US-6,964,814	11-2005	Fujii et al.	428/423.1
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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